## Notice of References Cited Application/Control No. 10/667,322 Examiner Brian Q. Le Applicant(s)/Patent Under Reexamination YEH ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name .	Classification
*	Α	US-6,341,016	01-2002	Malione, Michael	356/603
*	В	US-2004/0151365	08-2004	An Chang et al.	382/154
*	С	US-2003/0026475	02-2003	Yahashi et al.	382/154
*	D	US-7,239,312	07-2007	Urisaka et al.	345/419
*	· E	US-7,164,789	01-2007	Chen et al.	382/154
*	F	US-7,146,036	12-2006	An Chang et al.	382/154
*	G	US-7,092,563	08-2006	Shiratani, Fumiyuki	382/154
*	Н	US-7,013,040	03-2006	Shiratani, Fumiyuki	382/154
*	1	US-6,965,690	11-2005	Matsumoto, Yukinori	382/154
*	7	US-6,853,458	02-2005	Yahashi et al.	356/604
*	К	US-6,775,403	08-2004	Ban et al.	382/154
,	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Р				·	
	Q					·
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	S					·
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## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)					
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	W						
	×						

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.